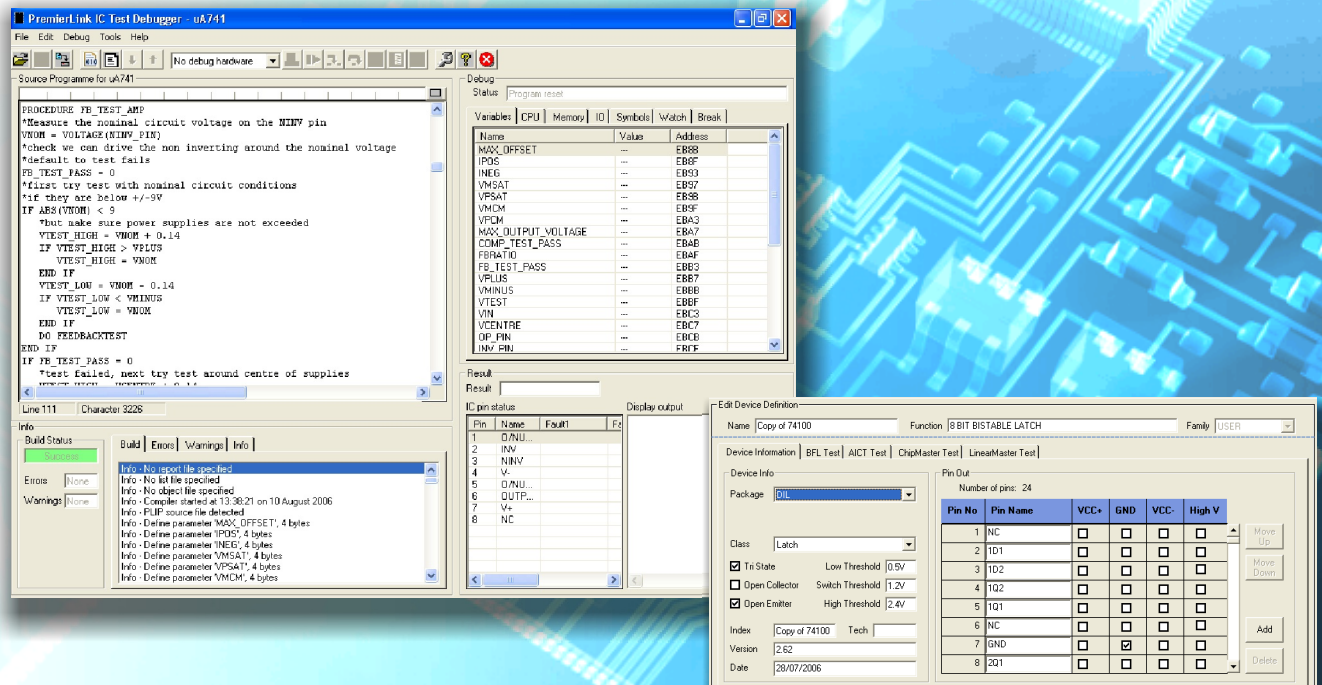


Write your OWN test programs to suit YOUR applications !

INCLUDES 



- Library development manager for IC configuration and test selection
- PLIP programming for full generation of new IC functional tests
- Compiler, debugger and active help integrated

PremierLink Functional Test Generating Software

A PC based software package that allows users to add new devices to the library, select a variety of tests and create new functional tests to suit special applications.

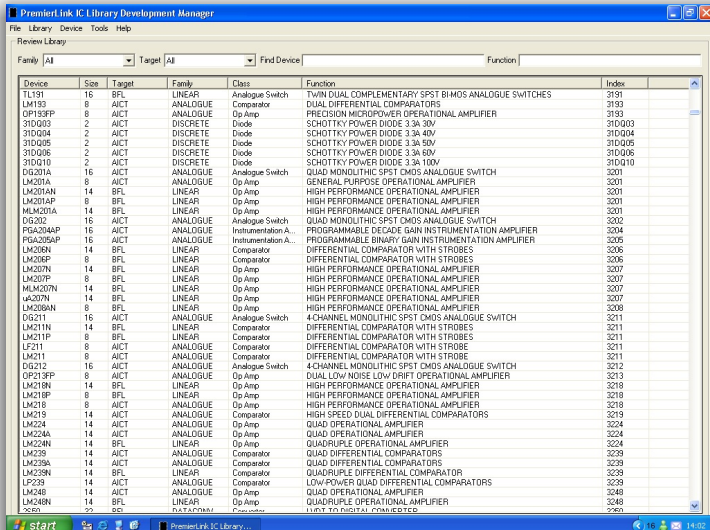
New IC functional tests can be created using *PremierLink IC Programming (PLIP)*, a high-level descriptive test programming language optimised for generation of both analogue and digital IC test programs.

PremierLink can also be used for board level applications where new routines can be written to test the integrity of a PCB.



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PremierLink Software

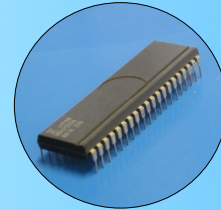


Library Development Manager

The Library Development Manager displays all the devices available in the built-in System 8 Library as well as the devices created by the user. It is the main interface for device selection or creation.

The device data is organised in 20 families and can be filtered using the drop down menus. Each device can have up to 4 targets, each containing specific information for the 4 products supported by PremierLink (BFL, AICT, ChipMaster Professional and LinearMaster Professional). A device name or function can also be typed in to facilitate the search. The list will be filtered to show only the entries containing the entered text. As an option, *intelligent sort* produces a more logical list by using the numeric part of the device name only.

All devices added by the user will be saved in the USER family.

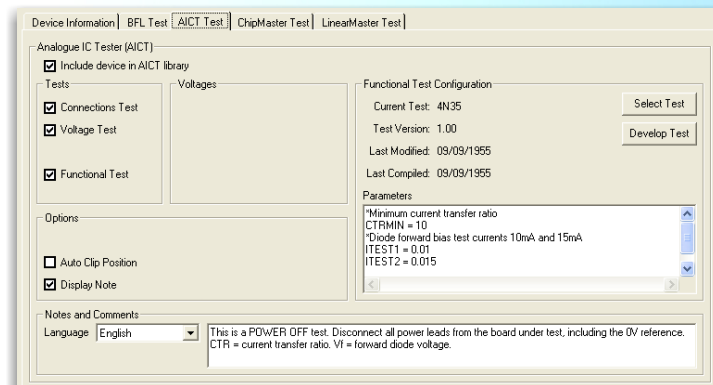
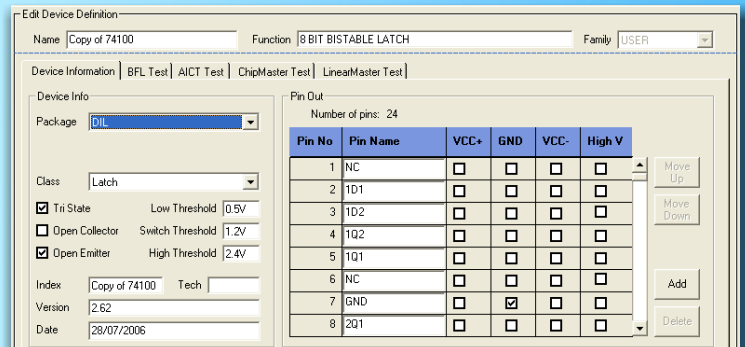


Device Definition

When a device is selected or created, the device definition window appears. This allows the user to enter the information related to the device as well as define its physical characteristics. The name and function will be used by the database for sorting. Parameters such as package, class, thresholds and output types may also be selected.

The power and ground pins of the new device must be specified using the pin out table.

Depending on the type of device selected, the target(s) required for the test can be enabled by selecting the tabs accordingly.

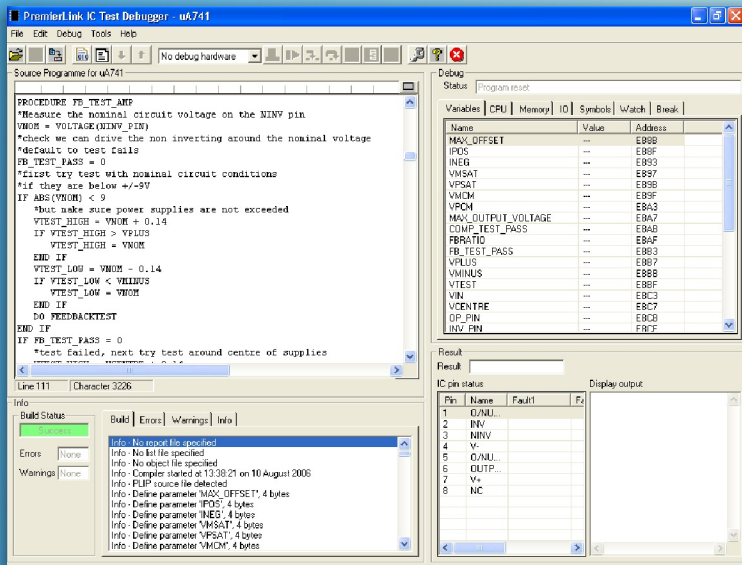


Test Configuration

This section is device and target specific. The type(s) of test to be applied to the new device can be selected by ticking the appropriate box(es). In order to make the tests more interactive, notes and comments can be added and will appear when the test is selected in the SYSTEM 8 Premier software.

If the new device has a similar function and pin out as another device in the library, the existing test program may be copied and used for the functional test.

However, a new test program may be created by clicking on *develop test*.



Programming Interface

The Programming Interface is designed for the generation and debugging of new functional IC tests. PLIP (PremierLink IC Programming) is a high level language designed specifically for test programming. The syntax is highly descriptive so that programs are, to a large extent, self commenting. However, comments can also be inserted if required.

The built in compiler generates binary data which can be executed in stand alone form by the integral debugger or combined into library files for use with SYSTEM 8 products.

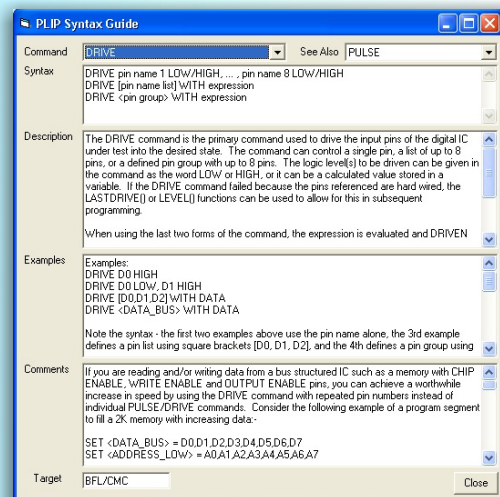
Up to 3 breakpoints can be added to the program where execution can be suspended and data can be examined.

The debugger allows the user to identify and fix the possible problems in the program, whilst connected to the hardware, before adding the new device to the library.

Online Active Help

PremierLink is supplied with an extensive online active help which can be accessed at any time during programming. This facility provides the user with a PLIP syntax guide for each command. The Active Help window is broken down into :

- A syntax section
- An extensive description of the command
- Concrete examples for illustration
- Additional comments (if applicable)
- Target field



Example

Complete program for a logic NAND gate.

```

INPUTS 1A,1B,2A,2B,3A,3B,4A,4B
INPUTS 1A,1B
DATA = 0
DO WHILE DATA <= 3
    DRIVE [1A,1B] WITH DATA
    IF LEVEL ([1A,1B]) = 3
        CHECK THAT 1Y IS LOW
    ELSE
        CHECK THAT 1Y IS HIGH
    END IF
    DATA = DATA + 1
END DO

```



INCLUDES

CompactLink

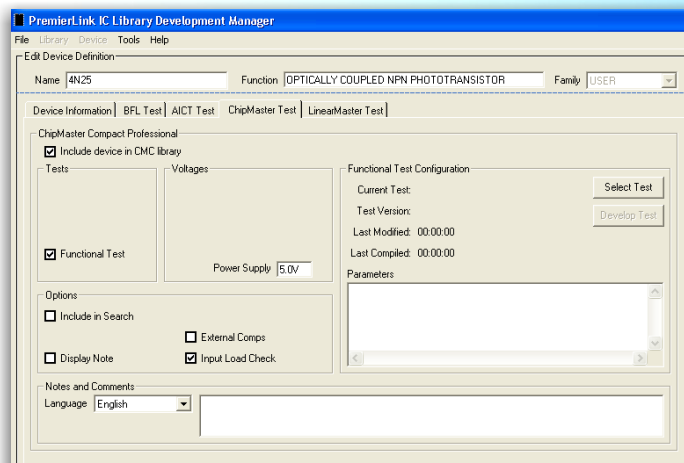
PremierLink is supplied with CompactLink, the functional test generating software for the Compact Professional Range (ChipMaster Professional and LinearMaster Professional).

CompactLink uses the same software interface as PremierLink and allows the user to add new devices and create new IC tests to suit special applications.

A connection to PC via RS-232 or USB (with adapter) is required.

Test Configuration

The Compact specific windows allow the user to setup a functional test for analogue or digital devices. For new test development, CompactLink uses the PLIP (PremierLink IC Programming) interface.



The Compact Professional Range connects to a PC via an RS-232 cable. The cable may be plugged in to a spare serial port or a spare USB port with use of an adapter.

Software updates (available on the internet) can be downloaded and programmed into the Compact units.

Linking the Compact Professional to a computer also allows the user to test a new program live on the unit with steps and toggle point functions.

PremierLink and CompactLink are provided with an activation dongle.

Notes :



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